



HAL
open science

Avalanches, precursors and finite size fluctuations in a mesoscopic model of amorphous plasticity

Mehdi Talamali, Viljo Petäjä, Damien Vandembroucq, Stéphane Roux

► **To cite this version:**

Mehdi Talamali, Viljo Petäjä, Damien Vandembroucq, Stéphane Roux. Avalanches, precursors and finite size fluctuations in a mesoscopic model of amorphous plasticity. 2011. hal-00579699v1

HAL Id: hal-00579699

<https://hal.science/hal-00579699v1>

Preprint submitted on 24 Mar 2011 (v1), last revised 4 Dec 2011 (v3)

HAL is a multi-disciplinary open access archive for the deposit and dissemination of scientific research documents, whether they are published or not. The documents may come from teaching and research institutions in France or abroad, or from public or private research centers.

L'archive ouverte pluridisciplinaire **HAL**, est destinée au dépôt et à la diffusion de documents scientifiques de niveau recherche, publiés ou non, émanant des établissements d'enseignement et de recherche français ou étrangers, des laboratoires publics ou privés.

Avalanches, precursors and finite size fluctuations in a mesoscopic model of amorphous plasticity

Mehdi Talamali,¹ Viljo Petäjä,² Damien Vandembroucq,¹ and Stéphane Roux³

¹ *Laboratoire PMMH, CNRS/ESPCI/Univ. Paris 6 UPMC/Univ. Paris 7 Diderot
10 rue Vauquelin, 75231 Paris cedex 05, France*

² *Laboratoire SVI, UMR 125 CNRS/Saint-Gobain
39 quai Lucien Lefranc, 93303 Aubervilliers cedex 05, France*

³ *LMT-Cachan, ENS de Cachan/CNRS-UMR 8535/Univ. Paris 6 UPMC/PRES UniverSud Paris
61 Avenue du Président Wilson - 94235 Cachan cedex, France*

(Dated: March 24, 2011)

We discuss avalanche and finite size fluctuations in a mesoscopic model to describe the shear plasticity of amorphous materials. Plastic deformation is assumed to occur through series of local reorganizations. Yield stress criteria are random while each plastic slip event induces a quadrupolar long range elastic stress redistribution. The model is discretized on a regular square lattice. Shear plasticity can be studied in this context as a depinning dynamic phase transition. We show evidence for a scale free distribution of avalanches $P(s) \propto S^{-\kappa}$ with a non trivial exponent $\kappa \approx 1.25$ significantly different from the mean field result $\kappa = 1.5$. Finite size effects allow for a characterization of the scaling invariance of the yield stress fluctuations observed in small samples. We finally identify a population of precursors of plastic activity and characterize its spatial distribution.

I. INTRODUCTION

While traditionally described in continuum mechanics by constitutive laws at macroscopic scale, it has progressively appeared in the last two decades that the mechanical behavior of materials was not as smooth and regular as anticipated. In particular crack propagation in brittle materials and plastic flow in crystalline solids have been shown to exhibit jerky motion and scale free spatio-temporal correlations [1–3].

Beyond its obvious fundamental interest, the understanding of intermittence and intrinsic fluctuations in mechanics of materials and their consequences at macroscopic scale is of direct importance for engineering applications: among other examples a quantitative assessment of risk of failure would allow to better determine security margins which stay rather uncontrolled (and often overestimated); a theoretical understanding of finite size effects would allow to model the mechanical behavior of small pieces, a question of crucial interest with the rapid technological development of MEMS and NEMS (Micro or Nano- Electro-Mechanical Systems).

Concepts such as avalanches and criticality have thus been growingly used in that context to describe and model fracture and plasticity. In particular, the paradigm of the depinning transition has shown extremely appealing to model such non-linear phenomena at mesoscopic scale [4–10]. Such a formalism indeed naturally captures the competition between the disorder of local thresholds (toughness for crack propagation, yield stress for plastic deformation) and elastic interactions which couple local mechanical events (crystallographic slip, crack advance). A critical threshold naturally emerges at macroscopic scale which separates a static phase (crack propagation or plastic deformation stops after a finite excursion) from a mobile phase (free propagation or deformation). As usual, this dynamic phase transition can be characterized by a set of critical exponents.

While crystalline plasticity or crack propagation rely on rather solid grounds (theory of dislocation and linear elastic fracture mechanics respectively), the understanding of plastic deformation in amorphous materials such as oxide or metallic glasses is still in its infancy. In absence of crystalline lattice, plasticity seems to originate from a series of very local structural rearrangements [11, 12]. Beyond this first level of description, any local reorganization has to be accommodated by the surrounding elastic matrix, and induces internal stress [13–15]. These local plastic events thus do not occur independently but in a strong correlated way.

We recently introduced a mesoscopic model of plasticity in amorphous materials [16]. Following an earlier work [9] we developed a scalar discrete model on a regular lattice with a random yield stress. The local slip occurring when the shear stress satisfies the plastic criterion is accompanied by an elastic stress redistribution of quadrupolar symmetry [17, 18] which corresponds to the elastic response of the surrounding matrix to this Eshelby-like plastic inclusion [19]. Although original due to the quadrupolar symmetry of the elastic interaction, one recognizes in this short description the two ingredients of a depinning model: a random threshold field and an elastic interaction.

In a previous paper [16] we focussed on the competition between localization and diffusion which natural emerges from the peculiar symmetry of the elastic interaction. Some directions being favored, plastic deformation forms shear bands which span the entire lattice. This localization is however not persistent and after they grow up to the size of the

system, shear bands tend to diffuse throughout the lattice. In particular we could make evidence for anisotropic strain correlations which are strikingly similar to those recently observed in an atomistic study of a binary Lennard-Jones glass under compression [20, 21].

In the present paper, a particular focus is given to the critical properties of the model. We recall in Section II the definition of the model and its salient properties. Avalanches are quantitatively characterized in Section III. Finite size fluctuations close to critical point are analyzed in Section IV. Characterization of avalanche precursor sites is discussed in Section V. Section VI concludes this paper.

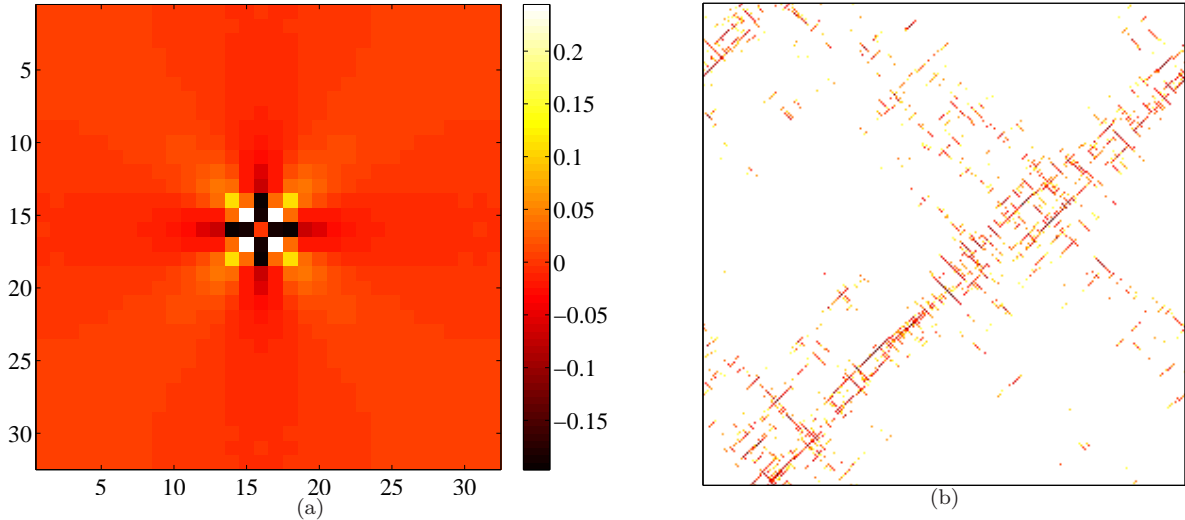


FIG. 1: (a) Map of the quadrupolar elastic interaction used in the model. The discretization is performed in Fourier space and an inverse Fourier transform gives in the direct space the Green function satisfying the bi-periodic boundary conditions of the problem. (b) Map of cumulated plastic activity obtained for a cumulated strain $\Delta\varepsilon = 0.01$ taken at $\varepsilon = 1.0$ (strain is expressed in arbitrary (infinitesimal) units). A clear localization of the plastic deformation is observed. Note that this localization behavior is non-persistent (see Ref. [16] for details on the competition between localization and diffusion of the plastic deformation.)

II. BRIEF DESCRIPTION OF THE MODEL

A detailed description of the model can be found in [16]. Let us simply summarize here the main points.

We consider an elastically homogeneous material in plane deformation geometry under shear. Discretization is performed on a square lattice with bi-periodic boundary conditions at a scale which is larger than the size of a typical rearrangement. This scale is to be large enough to allow the use of continuum elasticity, and to neglect elastic inhomogeneities. At a large scale, we impose a pure shear load $\sigma_{xx} = -\sigma_{yy}$, and $\sigma_{xy} = 0$.

A simplification consists of assuming that local rearrangements induce an elementary plastic shear with the same symmetry as the macroscopic imposed macroscopic shear. We thus consider neither volumetric change, nor orientation disorder for the shear principal axis at the microscopic scale. Consequently, although the model is based on a genuine 2D elastic description, the tensorial nature of the stress $\boldsymbol{\sigma}$ and strains $\boldsymbol{\varepsilon}$ plays no role. Scalar (equivalent) stress $\sigma \equiv \sigma_{xx} - \sigma_{yy}$ and strain $\varepsilon \equiv \varepsilon_{xx} - \varepsilon_{yy}$ can be defined. The latter scalar stress (resp. strain) component will be called “stress” (resp. “strain”) for simplicity in the following. The criterion for yielding characterizes the local configuration of atoms, and hence will display some variability. A local yield threshold for each discrete site \boldsymbol{x} as $\sigma_\gamma(\boldsymbol{x})$ is introduced, and will be treated as a random variable in the sequel. For all sites, the same statistical distribution will be used, chosen for simplicity as a uniform distribution over the interval $[0; 1]$. The specific form of this distribution plays no role in the scaling features addressed below.

The stress σ is a sum of the externally applied stress σ_{ext} and the residual stress σ_{res} induced by the previous rearrangements of other regions of the system. Thus, the local scalar yield criterion for site \boldsymbol{x} can be rewritten as

$$\sigma_{\text{ext}} + \sigma_{\text{res}}(\boldsymbol{x}) = \sigma_\gamma(\boldsymbol{x}). \quad (1)$$

where σ_γ is the local yield stress.

Once this criterion is satisfied at site \mathbf{x} , the material experiences there an incremental slip η increasing the local plastic strain: $\varepsilon_p(\mathbf{x}) \rightarrow \varepsilon_p(\mathbf{x}) + \eta$. Similarly to the yield thresholds, the slip value η is drawn randomly from the uniform distribution, $[0; d]$ if not otherwise stated. As shown in Fig. 1(a) this local slip induces in turn a quadrupolar elastic stress redistribution [16–18] $\sigma_{\text{res}}(r, \theta) \rightarrow \sigma_{\text{res}}(r, \theta) + \eta \cos(4\theta)/r^2$.

In order to account for the local structural change that occurred the local yield stress is renewed by drawing a new (uncorrelated) random value for $\sigma_\gamma(\mathbf{x})$. It is assumed that there is no persistence in the local yield stress.

Quasi-static driving conditions are considered, using *extremal dynamics*, *i.e.* the imposed external loading σ_{ext} is tuned at each time step, t , such that only one site can slip at a time:

$$\begin{aligned} \sigma_{\text{ext}}(t) &= \sigma_c \\ &= \min_{\mathbf{x}} [\sigma_\gamma(\mathbf{x}) - \sigma_{\text{res}}(\mathbf{x})] \\ &= \sigma_\gamma(\mathbf{x}^*(t)) - \sigma_{\text{res}}(\mathbf{x}^*(t)) \end{aligned} \quad (2)$$

where $\mathbf{x}^*(t)$ is the extremal site at time t . Note however, that “time”, t , is used here as a simple way of counting and ordering events. On average, time is simply proportional to the total plastic strain imposed on the system, $\langle \varepsilon_p \rangle = t d L^{-2} / 2$. The plastic strain field is thus simply

$$\varepsilon_p(\mathbf{x}, t) = \sum_1^t \eta(t) \delta(\mathbf{x} - \mathbf{x}^*(t)) \quad (3)$$

In Ref. [16], we discussed the mechanical behavior of this model and in particular we could make evidence for anisotropic plastic strain correlations, signalling the formation of shear bands as illustrated in Fig.1(b) which however were not persistent, and diffused throughout the system over long times. Under application of shear, a transient hardening stage was observed before the shear stress eventually saturates. This original phenomenon in the context of amorphous materials (in crystalline material hardening is usually associated with dislocation pinning by impurities or dislocation interactions) was interpreted as a consequence of the progressive exhaustion of the weakest sites of the system (reminiscent of self-organized critical systems). Plastic strain fluctuations were shown to exhibit a non trivial scaling : its standard deviation $\rho(\varepsilon_p)$ grows as $\rho(\varepsilon_p) \propto \varepsilon_p^\alpha$ with $\alpha \approx 0.75$ in the transient regime and, in the stationary regime, the power spectrum of plastic strain was shown to exhibit an anisotropic scaling $S(q, \theta) \propto a(\theta) q^{-\alpha(\theta)}$ with $\alpha(\theta)$ obeying a quadrupolar like symmetry. In particular, in the direction of the shear bands, we obtained $\alpha_{\pi/4} \approx 1.7$.

III. AVALANCHE BEHAVIOR

As discussed above, while intermittence and avalanches were first identified in earthquake dynamics, biological evolution [22] or magnetism [23, 24], the recent years have also shown their interest in the framework of mechanics of materials.

In the context of plasticity of crystalline materials, a significant amount of results have been obtained over the last decade (see e.g. the comprehensive review by M. Zaiser about scale invariance in plastic flow [2]). Acoustic emission measurements performed on ice or metal monocrystals have shown a power law distribution of the energy $P(E) \propto E^{-\kappa}$ with $\kappa \approx 1.6$ for ice [25] and $\kappa \approx 1.5$ for hcp metals and alloys [26]. The case of polycrystal is somewhat more complex since not only a grain size related cut-off appears in the avalanche distribution but the power law exponent is also significantly lowered [25]. Performing nano-indentation measurements on Nickel monocrystals, Dimiduk *et al* made evidence for a scale-free intermittent plastic flow and estimated $\kappa \approx 1.5 - 1.6$ [27].

Very recently analogous analysis could be performed on metallic glass samples. Sun *et al* [28] measured the distributions of stress drops occurring in the strain stress curve were for various metallic glass samples under compression. Scale free distributions were observed with a power law exponent $\kappa \in [1.37 - 1.49]$.

Various models have been designed which capture this avalanche behavior in plasticity at least from a qualitative point of view. Dislocation dynamics [1] and phase field [2] models have for instance been used in that purpose in the case of crystal plasticity. In the same context, Moretti and Zaiser [2, 29] developed at mesoscopic scale a model very similar to the one presented here since it integrates some local yield randomness. A significant difference stems from their account of short range interaction between dislocations moving on close slip planes. This local elastic interaction thus adds up and competes with the long range interaction ensuring compatibility. This model was then used to analyze slip avalanches in crystal plasticity [30], a scale free behavior was obtained with a power law exponent $\kappa = 1.5$. A special attention was given to the cut-off of the scale free behavior which could be associated to the finite stiffness of a testing machine and to the hardening behavior of the material.

In the field of amorphous plasticity, most numerical results were obtained using atomistic methods. Recently, in the framework of deformation of two-dimensional Lennard-Jones model glasses, Maloney and Robbins [20, 21] obtained a

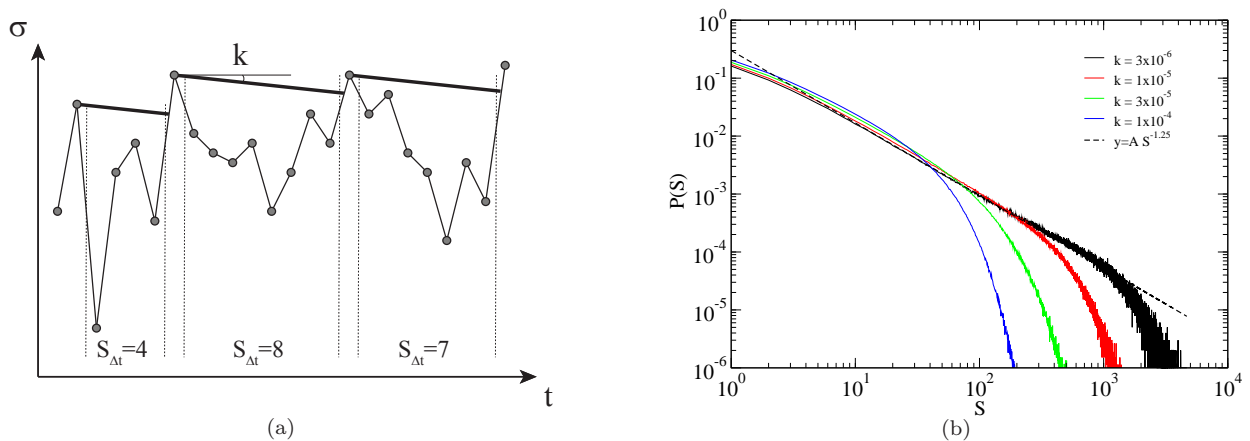


FIG. 2: (a) Sketch of the current yield stress (as obtained in extremal dynamics) (symbol \circ) and of the external stress when the system is coupled to a spring of constant k . Avalanches are defined as the intervals where the external stress remains larger than the yield stress. A new avalanche is initiated at the next maximum yield stress after arrest. (b) Distributions of avalanche sizes $P(S, k)$ for a system of size $L = 256$ and different values of spring constants $k = 10^{-6}, 10^{-5}, 10^{-4}, 10^{-3}, 10^{-2}$. A power-law of exponent $\kappa \approx -1.25$ (dashed line) is observed with a cut-off increasing as the spring constant decreases.

linear dependence of the mean avalanche size with system size. Lemaitre, Caroli and Chattoraj looked at the rate and thermal dependence of the avalanches distribution [31, 32] and showed that the athermal avalanche dynamics remain essentially unperturbed.

In a kinetic Monte Carlo study at mesoscopic scale, Homer *et al* [33] identified different (stress and temperature dependent) correlation behaviors of shear transformation zones leading either to an avalanche-like behavior or to an homogeneous flow. Still at mesoscopic scale, apart from the earlier version of the present model which considered antiplane geometry, mean fields models [34] have been developed by Ben-Zion, Dahmen and collaborators in the following of a model designed by Ben-Zion and Rice to capture earthquakes dynamics [35]. Again this class of models is very close to the one presented here with a significant difference concerning the elastic interaction which is assumed to be mean field. These models predict a universal scale free avalanche distribution with a power law exponent $\kappa = 1.5$.

A. Definition and scale free behavior

While avalanches are rather easily defined experimentally or in real-dynamics simulations, they need to be reconstructed from the fluctuating force signal in the case of depinning models driven through the extremal dynamics rules [36, 37]. Following Ref. [37], avalanches are defined by introducing a small but nonzero stiffness k in the external driving as illustrated in Fig. 2(a) where the bold line of slope $-k$ represents the external driving stress. With the increasing plastic strain the external stress is decreased linearly by a quantity $k\Delta t$, where Δt is the number of iteration steps from the avalanche initiation. As soon as the driving stress drops below the current critical value σ_c , the avalanche stops. The external spring is then loaded up to σ_c and trigs a new avalanche. Far from being artificial, this procedure naturally mimics the effect of the finite stiffness of an experimental testing machine, or the elasticity of the medium surrounding the active site [30]. Based on the latter argument, the thermodynamic limit of a large scale separation between that of the STZ, and that of the medium is reproduced for a vanishing stiffness, i.e. as for an ideal stress-controlled experiment. One may also note that an ideal strain-controlled experiment would be obtained for an infinite stiffness.

The present definition size of avalanches $S = \Delta t$ should not be confused with the duration of an avalanche measured in real time. The underlying extremal dynamics gives no information about real time scales. The size S of an avalanche is however directly related to the strain ε_S experienced by the medium through $\varepsilon_S = S\langle\eta\rangle/L^2$ where $\langle\eta\rangle$ is the average of the random incremental local slip η .

The avalanche size distributions $P(S, k)$ corresponding to various stiffness values k are shown in Fig. 2b. We obtain a scale free behavior over a domain bounded by a stiffness dependent cut-off (the lower the stiffness the larger the scaling domain). Up to the cut-off size S^* avalanche distributions follow a power law of exponent $-\kappa$ with $\kappa = 1.25 \pm 0.05$ over three decades. This excludes the mean field value $\kappa = 1.5$ as observed in mean-field models.

B. Avalanche cut-off

As discussed in [30] we thus could check that the introduction of a gaussian cut-off allows us to obtain reasonable fits of the full set of data:

$$P(S) \sim \Delta S^{-\kappa} \exp \left[- \left(\frac{S}{S^*} \right)^2 \right] \quad (4)$$

This gives us the opportunity to test the dependence of the avalanche cut-off S^* on the “machine stiffness” k . Note here that in the framework of extremal dynamics, obtaining a size-independent mechanical behavior (stress vs strain) requires the change of variable $\varepsilon = t/L^2$ to be performed, with t being the avalanche size as above defined. Similarly, this leads to rewrite the stiffness as $k = K/L^2$, K being an elastic constant independent of the system size. Looking at Fig. 3(a) which displays the dependence of the avalanche cut-off size, this allows to distinguish between two scaling regimes depending on whether the elastic constant K is smaller or larger than $K^* = 1$:

$$S^* \propto \begin{cases} L/K & \text{for } K < K^* \\ L/\sqrt{K} & \text{for } K > K^* \end{cases}, \quad (5)$$

In both cases we recover that the avalanche cut-off scales linearly with the system size L , consistently with results by Zaiser and Nikitas [30]. As illustrated in Fig. 4, a closer look at the spatial structure shows that the avalanches are highly anisotropic and once again we recover the quadrupolar symmetry of the elastic interaction. For large values of K , avalanches remain mainly one-dimensional while for lower values of K , two-dimensional-like patterns start to appear. One recovers here the competition between localization (at short times) and diffusion (at longer times) as discussed in Ref. [16].

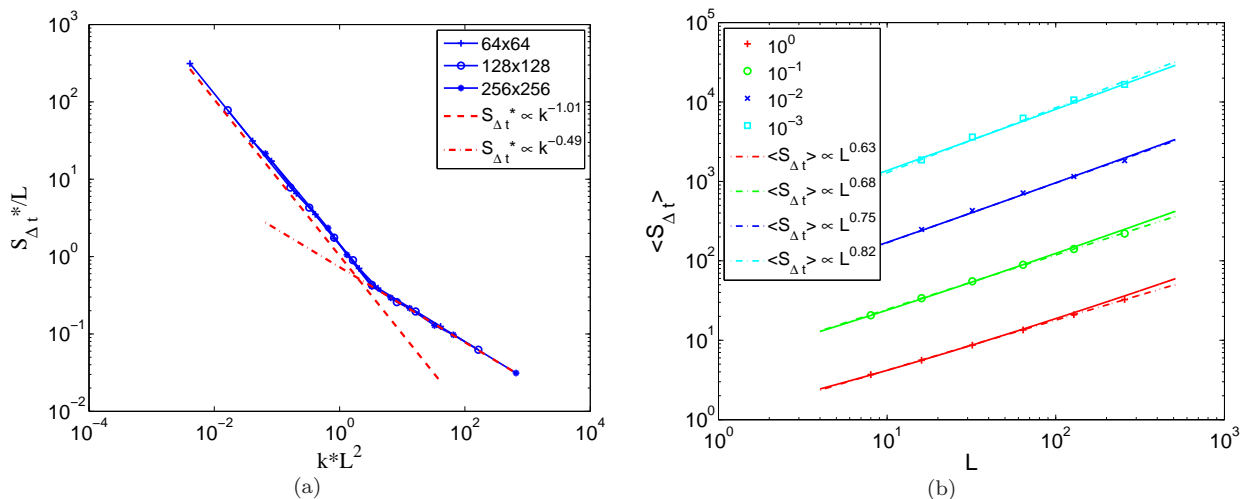


FIG. 3: (a) Scaling of the avalanche cut-off *vs* the rescaled stiffness $K = kL^2$. The cut-off S^* scales linearly with the system size L but exhibits either an inverse or an inverse square root dependence on the stiffness K depending on K is lower or larger than the characteristic stiffness $K^* = 1$. (b) Mean avalanche size dependence on system size L for stiffness values $K = 10^{-3}, 10^{-2}, 10^{-1}, 1$. The simulation data is shown as symbols while the analytic expression Eq. 6 provides the continuous curves. The dash-dotted lines show the apparent scaling associated to these different cases. The apparent scaling exponents are very dependent on the stiffness value.

C. Typical size of avalanches

With this knowledge about the avalanche cut-off the typical size $\langle S \rangle$ of an avalanche can thus be estimated,

$$\langle S \rangle \approx \frac{\int_1^{S^*} s^{1-\kappa} ds}{\int_1^{S^*} s^{-\kappa} ds} \approx \frac{\kappa - 1}{2 - \kappa} \frac{(L/K^v)^{2-\kappa} - 1}{1 - (L/K^v)^{1-\kappa}}. \quad (6)$$

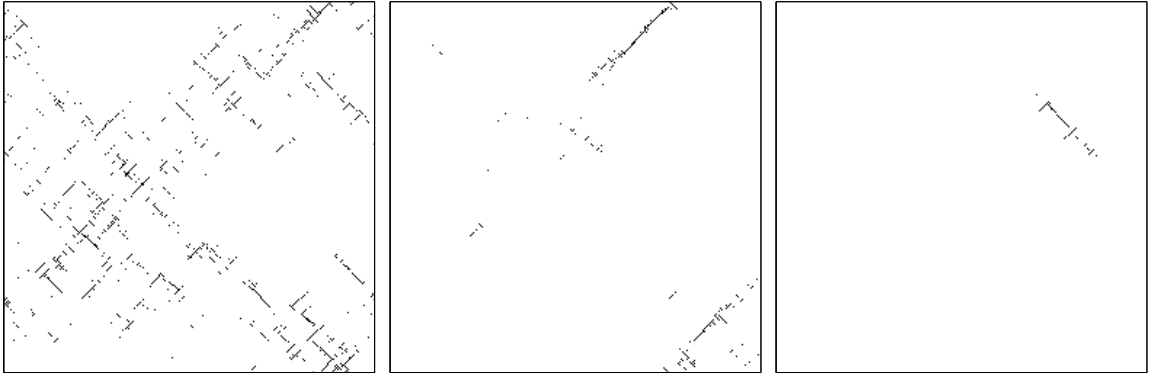


FIG. 4: Maps of cumulated plastic activity during avalanches obtained with stiffness values (from left to right) $K = 10^{-1}$, 10^0 and 10^1 for a system of size $L = 256$. The avalanche sizes were measured to be $S_{\Delta t} = 1616$, 324 and 81 respectively.

where $\kappa \approx 1.25$, $\nu = 1$ or $\nu = 1/2$ depending on whether $K < K^*$ or $K > K^*$.

In Fig. 3(b), we displayed the average avalanche size $\langle S \rangle$ versus the system size L for several values of the elastic constant K . Numerical results are well reproduced by the analytical equation Eq. (6). Note that as soon as the elastic constants approaches $K^* = 1$, the apparent scaling can be very different from the naive scaling obtained at very large sizes K or low values of K : $\langle S \rangle \propto (L/E)^\beta$ where $\beta = 2 - \kappa \approx 0.75$. The value of the machine stiffness in experimental testing is thus prone to affect the apparent scaling of the typical size of avalanches. Albeit the quality of the fits to power-laws is quite satisfactory, we believe that the apparent dependence of the exponent with k is the mere reflection of the corrections which can be rationalized by the above argument. The present results should be compared with those obtained by Maloney and Lemaître [13] who measured an average avalanche size $\langle S_{\Delta t} \rangle \propto L$ on Lennard-Jones two-dimensional model glasses under quasi-static shear and with those of Lemaître and Caroli [38], $\langle S_{\Delta t} \rangle \propto L$ or $L^{0.3}$ for a mean field model based on an effective mechanical noise accounting for the elastic interactions.

IV. CRITICAL THRESHOLD AND FINITE SIZE FLUCTUATIONS

As discussed in the introduction, the rapid development of micro and nano electromechanical systems is a strong motivation for the understanding of their mechanical behavior. In such systems the ratio between the “micro” size (grain domain, etc.) and the “macro” system size is low and strong fluctuations are expected from piece to piece.

In that context, the present modeling of amorphous plasticity as a depinning phenomenon is of high interest. As any phase transition, the depinning transition exhibit finite size effects which can be quantitatively characterized with the help of critical exponents.

In contrast to usual studies of criticality, the present context invites us to focus on the critical threshold rather than on the critical exponents. While the former is reputed of low interest since it depends on the microscopic details, it gives us here the yield stress value at macroscopic scale. The fluctuations of this threshold for finite systems will thus directly give the expected fluctuations of the yield stress for small pieces.

We develop below a study of finite-size effects which follow the lines of previous works about the depinning of elastic lines [39].

As defined in the description of the model, each elementary zone is characterized by a local plastic criterion $\sigma_c(\mathbf{x}) = \sigma_\gamma(\mathbf{x}) - \sigma_{\text{res}}(\mathbf{x})$ (where \mathbf{x} refers to the spatial location) which can be separated in two contributions: σ_γ corresponds to the yield threshold of the local structure in absence of internal stress; σ_{res} is the internal stress induced by the successive plastic reorganizations that have occurred in the material. For each configuration of the system, a loading that do not trigger any local slip event obeys $\sigma^{\text{ext}} < \sigma_c = \min_{\mathbf{x}} \sigma_c(\mathbf{x})$ and the macroscopic yield stress is then defined as the maximum value of this macroscopic load over the whole set of configurations, $\sigma^* = \max \sigma_c$; when the external stress lies below that value, σ^* , plastic deformation will eventually stop after a finite strain while above it the material can flow indefinitely. To recast this definition in the previous language of avalanches, the macroscopic yield stress is the one which corresponds to the existence of an infinite size avalanche at vanishing stiffness $k = 0$.

The distribution of these current plastic thresholds $P(\sigma_c)$ is shown in Fig. 5(a). Note that σ_c can take here negative or positive values since it is associated to a fluctuating part of the material properties. (Changing the material yield limit will trivially translate both the distribution and the critical threshold σ^* .) The same distribution is shown in 5(b) in logarithmic scale. The entire distribution depends on the local yield stress distribution, here a uniform distribution, and hence has no specific value. However, close to its maximum, the distribution contains only information relative to

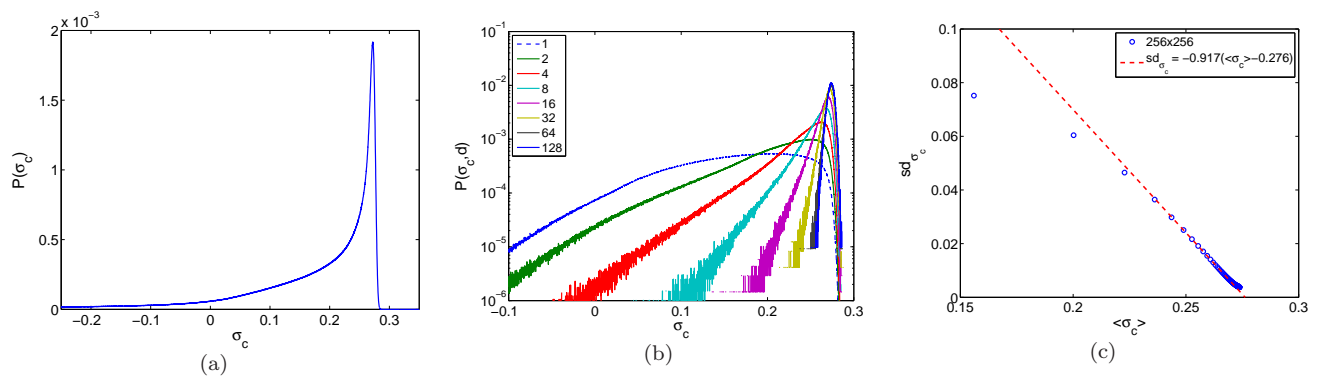


FIG. 5: (a) Distribution $P(\sigma_c)$ of the current yield stress σ_c sampled over time. The macroscopic yield stress σ^* is given by the maximum of the distribution. (b) Representation in semi-logarithmic coordinates of the conditional distributions $P(\sigma_c, \ell)$ such that the next slip event is located at a distance ℓ from the current point. $P(\sigma_c, \ell)$ can be interpreted as the distribution of yield stress fluctuations for a subsystem of size ℓ . (c) Dependence of the width w of the distributions $P(\sigma_c, \ell)$ vs. its mean value $\langle \sigma_c \rangle_\ell$ for different ℓ . The linear behavior obtained for large values of ℓ allows to estimate the asymptotic yield limit through extrapolation to $w = 0$.

macroscopically pinned or quasi pinned configurations. Hence the behavior of the distribution close to the maximum stress contains generic features which are difficult to extract from such a graph.

To isolate those universal features, it is proposed to part the distribution into conditional probability distribution functions depending on a characteristic which signals that the configuration is close to pinning. We chose the distance ℓ between successive slip events as a clear indication of such a pinned configuration. $P(\sigma_c, \ell)$ is introduced as the fraction of the initial distribution $P(\sigma_c)$ such that the plastic event occurred at a distance ℓ from the previous one. This trick gives us a simple way of analyzing finite size effects. Indeed, writing that plastic activity has to move by a distance ℓ simply means that over a domain of extension ℓ , the system has reached a pinned configuration. $P(\sigma_c, \ell)$ thus gives direct access to the distribution of effective thresholds for systems of size ℓ . We observe that the larger the distance (the system size), ℓ , the narrower the distribution $P(\sigma_c, \ell)$ and the closer its center from the maximum of the distribution $P(\sigma_c)$. This observation is rationalized in Fig. 5(c) where the width of these conditional distributions is plotted against their mean. We obtain a linear behavior, *i.e.*, these two quantities obey the same scaling. In particular, this means that extrapolating this linear behavior to a zero width (which would be obtained for an infinite system) allows us to give a precise estimate of the critical threshold σ^* .

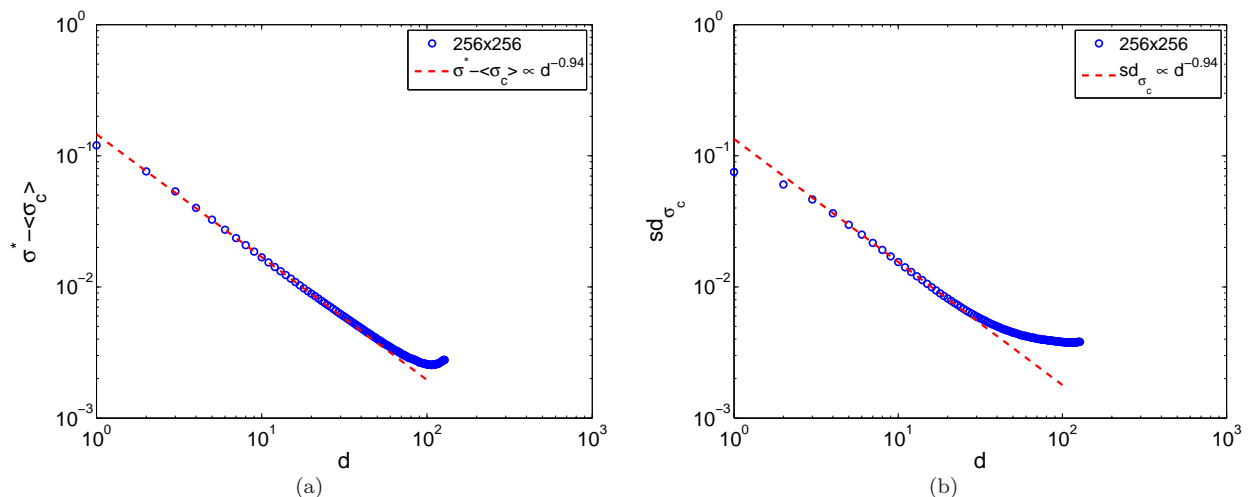


FIG. 6: (a) shows the difference between the asymptotic macroscopic yield stress, σ^* and the mean yield stress $\langle \sigma_c(\ell) \rangle$ vs. distance ℓ , for a system of size $L = 256$. A power-law fit of exponent $b \approx 0.94$ is shown as a dotted line. (b) is a plot of the standard deviation of depinning stress w as a function of the distance ℓ , for a system of size $L = 256$. A similar power-law fit of exponent $b \approx 0.94$ is shown as a dotted line.

The precise knowledge of the critical threshold gives us the opportunity to characterize not only the scaling behavior of the finite size fluctuations of the yield stress but also of the distance between the mean yield stress and the critical threshold. The two scaling behaviors are displayed in Fig. 6. We see that for a typical size ℓ both the width $w(\ell)$ of the yield stress fluctuations and the distance to threshold $\sigma^* - \sigma_c(\ell)$ obey the same scaling:

$$w(\ell) \propto \ell^{-b}; \quad \sigma^* - \sigma_c(\ell) \propto \ell^{-b} \quad \text{with } b \approx 0.94 \quad (7)$$

The macroscopic yield stress is hampered by finite size systematic corrections roughly inversely proportional to the system size. While in the context of elastic line depinning, a similar power-law correction was observed, the exponent b could be related to the roughness exponent [39], in the present case, we could not build a similar scaling relation.

V. PLASTIC PRECURSORS

As discussed in Ref. [16], the plastic strain obeys a strong anisotropic scaling resulting from the quadrupolar symmetry of the elastic stress redistribution. Most of the plastic events occur consecutively to a previous plastic event located along a direction at $\pm\pi/4$ (maximum shear directions).

However, it appears that only a tiny fraction of the sites is prone to slip. It is possible to distinguish these precursory sites when looking at the full distribution of the local plastic thresholds $\sigma_c(\mathbf{x})$. Such distributions are displayed in Fig. 7(a) for different system sizes. The dashed vertical line at the abscissa of the critical threshold σ^* allows us to separate two populations. The left part corresponds to the weakest sites of the lattice. For one particular configuration, the weakest site gives the current yield stress σ_c . The right part corresponds to the sub-critical sites, their local threshold being larger than the critical value σ^* they are unconditionally stable. For one configuration however, not only the weakest site but also a few others can be characterized by an overcritical local threshold *i.e.* $\sigma_c(\mathbf{x}) < \sigma^*$. They are thus very likely to initiate a slip event, and hence can be termed ‘‘precursors’’. A scaling analysis of this population is of interest. It is clear from Fig. 7(a) that the fraction of precursors decreases when the size L of the system increases. The right panel 7(b) shows the size dependence of this population in logarithmic scale. We obtain $P[\sigma_c(\mathbf{x}) < \sigma^*] \propto L^{-s}$ with $s \approx 1.34$. This scaling can be interpreted as the fact that these precursory sites live on a fractal support of dimension $d_F = 2 - s \approx 0.66$.

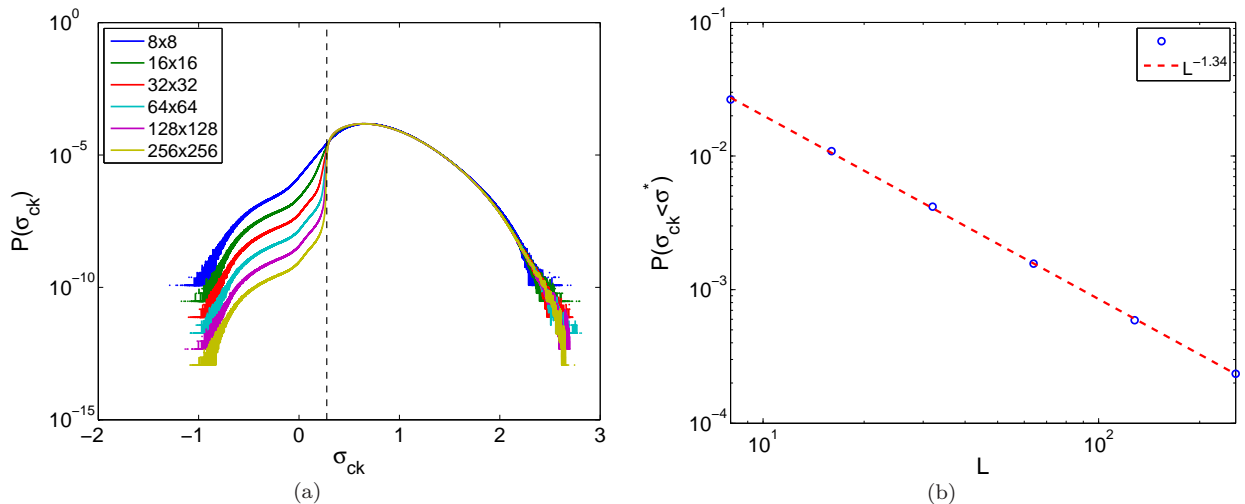


FIG. 7: (a) Distribution of individual depinning stress $P(\sigma_c(\mathbf{x}))$ for different system sizes $L = 8, 16, 32, 64, 128$ and 256 ; The dotted line indicates the macroscopic yield threshold σ^* : The overcritical part ($\sigma_{ck} < \sigma^*$) depends on L (in contrast to the subcritical one). (b) The relative weight of the overcritical part $P(\sigma_{ck} < \sigma^*)$ is observed to scale as a power-law of the system size. $P(\sigma_{ck} < \sigma^*) \propto L^{-s}$ with $s \approx 1.34$.

The identification of a set of precursors can be illustrated graphically. In Fig. 8 we superimposed the plastic activity observed during avalanches with the set of identified precursors (represented as colored dots) just before the avalanche take place. One can clearly see that avalanches indeed initiate from some of these over-critical sites. One also observes a striking intermittence of this population which can fluctuate from one to a few tens. It is of interest to follow the fate of these precursors during the avalanche. The red spots indicate sites taking part in the avalanche. Blue and green dots indicate sites not taking part of the avalanche but at the end of the latter, green dots are still over-critical

while blue ones are no longer over-critical. This possibility of healing is a specificity of the present model. Indeed, in contrast to the case of a depinning front where elastic coupling does not change sign, the quadrupolar interaction is positive or negative depending on the direction and thus has either a stabilizing effect (over-critical sites are sent back in the sub-critical part of the distribution) or a destabilizing effect. However, the presence of green dots indicate that not all overcritical sites are exhausted during an avalanche. Only late plastic events will be initiated there. A large part of the dynamics of the model is thus related to this population of precursors which seems to encode a long term information.

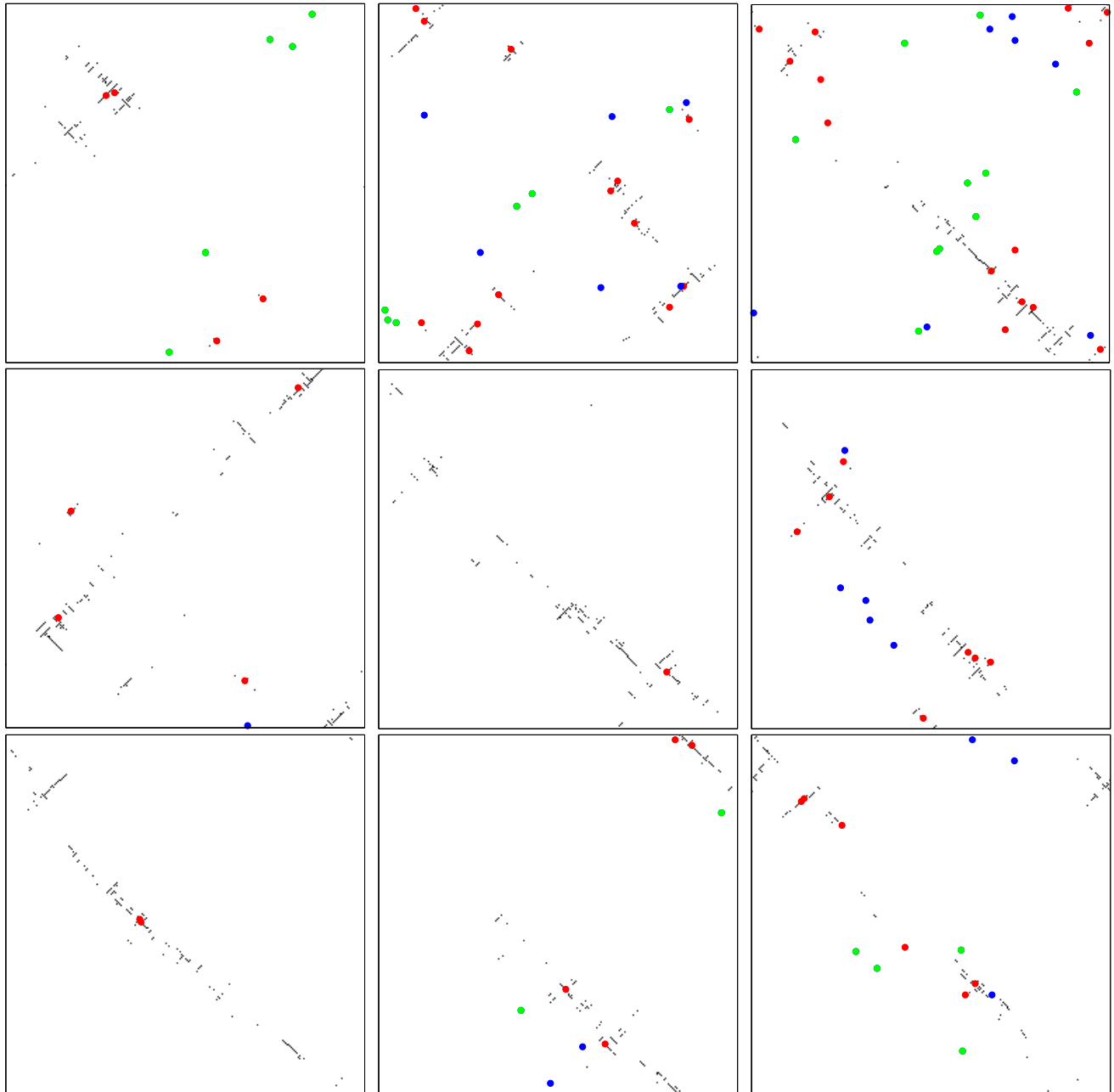


FIG. 8: Maps of cumulated plastic activity during avalanches obtained with stiffness values $K = 1$ for a system of size $L = 256$. The colored dots indicate the location of precursors just before the avalanche takes place. Red dots are part of the avalanche, green and blue dots are not part of the avalanche but at the end of the later green dots are still overcritical while blue dots are no longer over-critical, they have been healed during the avalanche.

VI. CONCLUSION

The present meso-model of amorphous plasticity, based on the competition between a local yield stress randomness and long range elastic interaction allowed us to obtain non trivial results about avalanche statistics and finite-size effects. In particular the exponent reported here for the scale free avalanche distribution, $\kappa \approx 1.25$ is significantly different from the mean field value ($3/2$). This suggests that a faithful account of the elastic stress redistribution due to local restructuring is indeed a crucial ingredient in the modeling of amorphous plasticity to capture faithfully collective effects. Although original due to this quadrupolar interaction, the present model can still be discussed in the framework of the depinning transition. This allowed us to track the finite size fluctuation and systematic size effect of the macroscopic yield stress. In addition, a set of precursory sites of having a fractal support has been identified.

-
- [1] M. Miguel, A. Vespignani, S. Zapperi, J. Weiss, and J.-R. Grasso, *Nature* **410**, 667 (2001).
 - [2] M. Zaiser, *Adv. Phys.* **55**, 185 (2006).
 - [3] D. Bonamy, *J. Phys. D: Appl. Phys.* **42**, 2114014 (2009).
 - [4] J. Schmittbuhl, S. Roux, J. P. Vilotte, and K. J. Måløy, *Phys. Rev. Lett.* **74**, 1787 (1995).
 - [5] P. Daguier, E. Bouchaud, and G. Lapasset, *Europhys. Lett.* **31**, 367 (1995).
 - [6] S. Ramanathan, D. Ertaş, and D. S. Fisher, *Phys. Rev. Lett.* **79**, 873 (1997).
 - [7] D. S. Fisher, *Phys. Rep.* **301**, 113 (1998).
 - [8] M. Zaiser, *Mater. Sci. Eng. A* **309-310**, 304 (2001).
 - [9] J.-C. Baret, D. Vandembroucq, and S. Roux, *Phys. Rev. Lett.* **89**, 195506 (2002).
 - [10] P. Moretti, M. C. Miguel, M. Zaiser, and S. Zapperi, *Phys. Rev. B* **69**, 214103 (2004).
 - [11] M. L. Falk and J. S. Langer, *Phys. Rev. E* **57**, 7192 (1998).
 - [12] A. S. Argon, *Acta Metall.* **27**, 47 (1979).
 - [13] C. E. Maloney and A. Lemaître, *Phys. Rev. Lett.* **93**, 016001 (2004).
 - [14] A. Tanguy, F. Leonforte, and J.-L. Barrat, *Eur. Phys. J. E* **20**, 355 (2006).
 - [15] D. Rodney and C. A. Schuh, *Phys. Rev. Lett.* **102**, 235503 (2009).
 - [16] M. Talamali, V. Petäjä, S. Roux, and D. Vandembroucq, preprint, arxiv:1005.2463 (2010).
 - [17] G. Picard, A. Ajdari, F. Lequeux, and L. Bocquet, *Eur. Phys. J. E* **71**, 010501(R) (2005).
 - [18] M. Talamali, V. Petäjä, D. Vandembroucq, and S. Roux, *Phys. Rev. E* **78**, 016109 (2008).
 - [19] J. D. Eshelby, *Proc. Roy. Soc. A* **241**, 376 (1957).
 - [20] C. E. Maloney and M. O. Robbins, *J. Phys. Cond. Matt.* **20**, 244128 (2008).
 - [21] C. E. Maloney and M. O. Robbins, *Phys. Rev. Lett.* **102**, 225502 (2009).
 - [22] P. Bak, *How Nature works* (Copernicus Press, New York, 1996).
 - [23] J. P. Sethna, K. A. Dahmen, S. Kharta, J. A. Krumhansl, B. W. Roberts, and J. D. Shore, *Phys. Rev. Lett.* **70**, 3347 (1993).
 - [24] S. Zapperi, P. Cizeau, G. Durin, and H. E. Stanley, *Phys. Rev. B* **58**, 6353 (1998).
 - [25] T. Richeton and J. Weiss, *Acta. Mater.* **53**, 4463 (2006).
 - [26] T. Richeton, P. Dobron, F. Chmelik, J. Weiss, and F. Louchet, *Mater. Sci. Eng. A* **424**, 190 (2006).
 - [27] D. Dimiduk, C. Woodward, and R. L. M. Uchic, *Science* **26**, 1188 (2006).
 - [28] B. A. Sun, H. B. Yu, W. Jiao, H. Y. Bai, D. Q. Zhao, and W. H. Wang, *Phys. Rev. Lett.* **105**, 035501 (2010).
 - [29] M. Zaiser and P. Moretti, *J. Stat. Mech.* **P08004**, 79 (2005).
 - [30] M. Zaiser and P. Nikitas, *J. Stat. Mech.* **P04013**, 1 (2007).
 - [31] A. Lemaître and C. Caroli, *Phys. Rev. Lett.* **103**, 065501 (2009).
 - [32] J. Chattoraj, C. Caroli, and A. Lemaître, *Phys. Rev. Lett.* **105**, 266001 (2010).
 - [33] E. R. Homer, D. Rodney, and C. A. Schuh, *Phys. Rev. B* **81**, 064204 (2010).
 - [34] K. A. Dahmen, Y. Ben-Zion, and J. T. Uhl, *Phys. Rev. Lett.* **102**, 175501 (2009).
 - [35] Y. Ben-Zion and J. R. Rice, *J. Geophys. Res.* **98**, 14109 (1993).
 - [36] M. Paczuski, S. Maslov, and P. Bak, *Phys. Rev. E* **53**, 414 (1996).
 - [37] A. Tanguy, M. Gounelle, and S. Roux, *Phys. Rev. E* **58**, 1577 (1998).
 - [38] A. Lemaître and C. Caroli, arxiv:cond-mat/0609689v1 (2006).
 - [39] D. Vandembroucq, R. Skoe, and S. Roux, *Phys. Rev. E* **70**, 051101 (2004).